Search Notes

Appli	cation/Control	No.			

10/615,416

Examiner

Pablo Whaley

Applicant(s)/Patent under Reexamination

WISHART ET AL.

Art Unit

1631

	SEARCHED			
Class	Subclass	Date	Examiner	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Google Scholar: NMR, FID, contaminant, filtering	9/21/2007	PW		
Inventor Search: Palm	9/21/2007	PW		